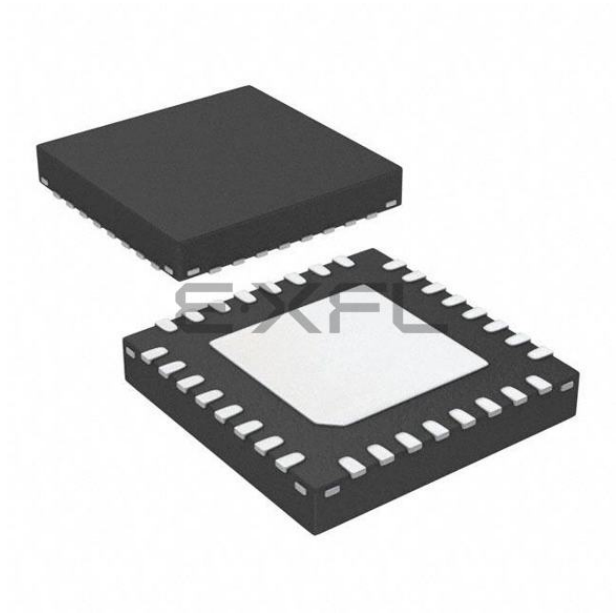

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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Not For New Designs
Core Processor	CIP-51 8051
Core Size	8-Bit
Speed	50MHz
Connectivity	I²C, SMBus, SPI, UART/USART
Peripherals	Brown-out Detect/Reset, POR, PWM, WDT
Number of I/O	29
Program Memory Size	32KB (32K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	2.25K x 8
Voltage - Supply (Vcc/Vdd)	2.2V ~ 3.6V
Data Converters	A/D 20x10/12b SAR; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	32-UFQFN Exposed Pad
Supplier Device Package	32-QFN (4x4)
Purchase URL	https://www.e-xfl.com/product-detail/silicon-labs/efm8bb31f32g-b-qfn32r

3.4 Clocking

The CPU core and peripheral subsystem may be clocked by both internal and external oscillator resources. By default, the system clock comes up running from the 24.5 MHz oscillator divided by 8.

The clock control system offers the following features:

- Provides clock to core and peripherals.
- 24.5 MHz internal oscillator (HFOSC0), accurate to ±2% over supply and temperature corners.
- 49 MHz internal oscillator (HFOSC1), accurate to ±2% over supply and temperature corners.
- 80 kHz low-frequency oscillator (LFOSC0).
- External RC, CMOS, and high-frequency crystal clock options (EXTCLK).
- Clock divider with eight settings for flexible clock scaling:
  - Divide the selected clock source by 1, 2, 4, 8, 16, 32, 64, or 128.
  - HFOSC0 and HFOSC1 include 1.5x pre-scalers for further flexibility.

3.5 Counters/Timers and PWM

Programmable Counter Array (PCA0)

The programmable counter array (PCA) provides multiple channels of enhanced timer and PWM functionality while requiring less CPU intervention than standard counter/timers. The PCA consists of a dedicated 16-bit counter/timer and one 16-bit capture/compare module for each channel. The counter/timer is driven by a programmable timebase that has flexible external and internal clocking options. Each capture/compare module may be configured to operate independently in one of five modes: Edge-Triggered Capture, Software Timer, High-Speed Output, Frequency Output, or Pulse-Width Modulated (PWM) Output. Each capture/compare module has its own associated I/O line (CEXn) which is routed through the crossbar to port I/O when enabled.

- 16-bit time base
- Programmable clock divisor and clock source selection
- Up to six independently-configurable channels
- 8, 9, 10, 11 and 16-bit PWM modes (center or edge-aligned operation)
- Output polarity control
- Frequency output mode
- Capture on rising, falling or any edge
- Compare function for arbitrary waveform generation
- Software timer (internal compare) mode
- Can accept hardware “kill” signal from comparator 0 or comparator 1

I2C Slave (I2CSLAVE0)

The I2C Slave interface is a 2-wire, bidirectional serial bus that is compatible with the I2C Bus Specification 3.0. It is capable of transferring in high-speed mode (HS-mode) at speeds of up to 3.4 Mbps. Firmware can write to the I2C interface, and the I2C interface can autonomously control the serial transfer of data. The interface also supports clock stretching for cases where the core may be temporarily prohibited from transmitting a byte or processing a received byte during an I2C transaction. This module operates only as an I2C slave device.

The I2C module includes the following features:

- Standard (up to 100 kbps), Fast (400 kbps), Fast Plus (1 Mbps), and High-speed (3.4 Mbps) transfer speeds
- Support for slave mode only
- Clock low extending (clock stretching) to interface with faster masters
- Hardware support for 7-bit slave address recognition
- Transmit and receive FIFOs (two byte) to help increase throughput in faster applications
- Hardware support for multiple slave addresses with the option to save the matching address in the receive FIFO

16-bit CRC (CRC0)

The cyclic redundancy check (CRC) module performs a CRC using a 16-bit polynomial. CRC0 accepts a stream of 8-bit data and posts the 16-bit result to an internal register. In addition to using the CRC block for data manipulation, hardware can automatically CRC the flash contents of the device.

The CRC module is designed to provide hardware calculations for flash memory verification and communications protocols. The CRC module supports the standard CCITT-16 16-bit polynomial (0x1021), and includes the following features:

- Support for CCITT-16 polynomial
- Byte-level bit reversal
- Automatic CRC of flash contents on one or more 256-byte blocks
- Initial seed selection of 0x0000 or 0xFFFF

Configurable Logic Units (CLU0, CLU1, CLU2, and CLU3)

The Configurable Logic block consists of multiple Configurable Logic Units (CLUs). CLUs are flexible logic functions which may be used for a variety of digital functions, such as replacing system glue logic, aiding in the generation of special waveforms, or synchronizing system event triggers.

- Four configurable logic units (CLUs), with direct-pin and internal logic connections
- Each unit supports 256 different combinatorial logic functions (AND, OR, XOR, muxing, etc.) and includes a clocked flip-flop for synchronous operations
- Units may be operated synchronously or asynchronously
- May be cascaded together to perform more complicated logic functions
- Can operate in conjunction with serial peripherals such as UART and SPI or timing peripherals such as timers and PCA channels
- Can be used to synchronize and trigger multiple on-chip resources (ADC, DAC, Timers, etc.)
- Asynchronous output may be used to wake from low-power states

Low Current Comparators (CMP0, CMP1)

An analog comparator is used to compare the voltage of two analog inputs, with a digital output indicating which input voltage is higher. External input connections to device I/O pins and internal connections are available through separate multiplexers on the positive and negative inputs. Hysteresis, response time, and current consumption may be programmed to suit the specific needs of the application.

The comparator includes the following features:

- Up to 10 (CMP0) or 9 (CMP1) external positive inputs
- Up to 10 (CMP0) or 9 (CMP1) external negative inputs
- Additional input options:
  - Internal connection to LDO output
  - Direct connection to GND
  - Direct connection to VDD
  - Dedicated 6-bit reference DAC
- Synchronous and asynchronous outputs can be routed to pins via crossbar
- Programmable hysteresis between 0 and ±20 mV
- Programmable response time
- Interrupts generated on rising, falling, or both edges
- PWM output kill feature

3.8 Reset Sources

Reset circuitry allows the controller to be easily placed in a predefined default condition. On entry to this reset state, the following occur:

- The core halts program execution.
- Module registers are initialized to their defined reset values unless the bits reset only with a power-on reset.
- External port pins are forced to a known state.
- Interrupts and timers are disabled.

All registers are reset to the predefined values noted in the register descriptions unless the bits only reset with a power-on reset. The contents of RAM are unaffected during a reset; any previously stored data is preserved as long as power is not lost. By default, the Port I/O latches are reset to 1 in open-drain mode, with weak pullups enabled during and after the reset. Optionally, firmware may configure the port I/O, DAC outputs, and precision reference to maintain state through system resets other than power-on resets. For Supply Monitor and power-on resets, the RSTb pin is driven low until the device exits the reset state. On exit from the reset state, the program counter (PC) is reset, and the system clock defaults to an internal oscillator. The Watchdog Timer is enabled, and program execution begins at location 0x0000.

Reset sources on the device include the following:

- Power-on reset
- External reset pin
- Comparator reset
- Software-triggered reset
- Supply monitor reset (monitors VDD supply)
- Watchdog timer reset
- Missing clock detector reset
- Flash error reset

3.9 Debugging

The EFM8BB3 devices include an on-chip Silicon Labs 2-Wire (C2) debug interface to allow flash programming and in-system debugging with the production part installed in the end application. The C2 interface uses a clock signal (C2CK) and a bi-directional C2 data signal (C2D) to transfer information between the device and a host system. See the C2 Interface Specification for details on the C2 protocol.

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Stop Mode—Core halted and all clocks stopped,Internal LDO On, Supply monitor off.	I_{DD}		—	120	740	µA
Shutdown Mode—Core halted and all clocks stopped,Internal LDO Off, Supply monitor off.	I_{DD}		—	0.2	4.5	µA
Analog Peripheral Supply Currents (-40 °C to +125 °C)						
High-Frequency Oscillator 0	I_{HFOSC0}	Operating at 24.5 MHz, T_A = 25 °C	—	120	135	µA
High-Frequency Oscillator 1	I_{HFOSC1}	Operating at 49 MHz, T_A = 25 °C	—	770	1200	µA
Low-Frequency Oscillator	I_{LFOSC}	Operating at 80 kHz, T_A = 25 °C	—	3.7	6	µA
ADC0[4]	I_{ADC}	High Speed Mode 1 Msps, 10-bit conversions Normal bias settings V_{DD} = 3.0 V	—	1210	1600	µA
		Low Power Mode 350 ksps, 12-bit conversions Low power bias settings V_{DD} = 3.0 V	—	415	560	µA
Internal ADC0 Reference[5]	I_{VREFFS}	High Speed Mode	—	700	790	µA
		Low Power Mode	—	170	210	µA
On-chip Precision Reference	I_{VREFP}		—	75	—	µA
Temperature Sensor	I_{TSENSE}		—	68	120	µA
Digital-to-Analog Converters (DAC0, DAC1, DAC2, DAC3)[6]	I_{DAC}		—	125	—	µA
Comparators (CMP0, CMP1)	I_{CMP}	CPMD = 11	—	0.5	—	µA
		CPMD = 10	—	3	—	µA
		CPMD = 01	—	10	—	µA
		CPMD = 00	—	25	—	µA
Comparator Reference	I_{CPREF}		—	24	—	µA
Voltage Supply Monitor (VMON0)	I_{VMON}		—	15	20	µA

4.1.6 Internal Oscillators

Table 4.6. Internal Oscillators

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
High Frequency Oscillator 0 (24.5 MHz)						
Oscillator Frequency	f_{HFOSC0}	Full Temperature and Supply Range	24	24.5	25	MHz
Power Supply Sensitivity	PSS_{HFOSC0}	T_A = 25 °C	—	0.5	—	%/V
Temperature Sensitivity	TS_{HFOSC0}	V_{DD} = 3.0 V	—	40	—	ppm/°C
High Frequency Oscillator 1 (49 MHz)						
Oscillator Frequency	f_{HFOSC1}	Full Temperature and Supply Range	48.02	49	49.98	MHz
Power Supply Sensitivity	PSS_{HFOSC1}	T_A = 25 °C	—	300	—	ppm/V
Temperature Sensitivity	TS_{HFOSC1}	V_{DD} = 3.0 V	—	103	—	ppm/°C
Low Frequency Oscillator (80 kHz)						
Oscillator Frequency	f_{LFOSC}	Full Temperature and Supply Range	75	80	85	kHz
Power Supply Sensitivity	PSS_{LFOSC}	T_A = 25 °C	—	0.05	—	%/V
Temperature Sensitivity	TS_{LFOSC}	V_{DD} = 3.0 V	—	65	—	ppm/°C

4.1.7 External Clock Input

Table 4.7. External Clock Input

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
External Input CMOS Clock Frequency (at EXTCLK pin)	f_{CMOS}		0	—	50	MHz
External Input CMOS Clock High Time	t_{CMOSH}		9	—	—	ns
External Input CMOS Clock Low Time	t_{CMOSL}		9	—	—	ns

4.1.8 Crystal Oscillator

Table 4.8. Crystal Oscillator

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Crystal Frequency	f_{XTAL}		0.02	—	25	MHz
Crystal Drive Current	I_{XTAL}	XFCN = 0	—	0.5	—	µA
		XFCN = 1	—	1.5	—	µA
		XFCN = 2	—	4.8	—	µA
		XFCN = 3	—	14	—	µA
		XFCN = 4	—	40	—	µA
		XFCN = 5	—	120	—	µA
		XFCN = 6	—	550	—	µA
		XFCN = 7	—	2.6	—	mA

4.1.12 DACs

Table 4.12. DACs

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Resolution	N_{bits}			12		Bits
Throughput Rate	f_S		—	—	200	ksps
Integral Nonlinearity	INL	DAC0 and DAC2 T_A = -40 °C to 125 °C (I-grade parts only)	-11.5	-1.77 / 1.56	11.5	LSB
		DAC0 and DAC3 T_A = -40 °C to 125 °C (I-grade parts only)	-13.5	-2.73 / 1.11	13.5	LSB
Differential Nonlinearity	DNL		-1	—	1	LSB
Output Noise	VREF = 2.4 V f_S = 0.1 Hz to 300 kHz		—	110	—	μV_{RMS}
Slew Rate	SLEW		—	±1	—	V/µs
Output Settling Time to 1% Full-scale	t_{SETTLE}	V_{OUT} change between 25% and 75% Full Scale	—	2.6	5	µs
Power-on Time	t_{PWR}		—	—	10	µs
Voltage Reference Range	V_{REF}		1.15	—	V_{DD}	V
Power Supply Rejection Ratio	PSRR	DC, V_{OUT} = 50% Full Scale	—	78	—	dB
Total Harmonic Distortion	THD	V_{OUT} = 10 kHz sine wave, 10% to 90%	54	—	—	dB
Offset Error	E_{OFF}	VREF = 2.4 V	-8	0	8	LSB
Full-Scale Error	E_{FS}	VREF = 2.4 V	-13	±5	13	LSB
External Load Impedance	R_{LOAD}		2	—	—	kΩ
External Load Capacitance[1]	C_{LOAD}		—	—	100	pF

Note:

1. No minimum external load capacitance is required. However, under low loading conditions, it is possible for the DAC output to glitch during start-up. If smooth start-up is required, the minimum loading capacitance at the pin should be a minimum of 10 pF.

4.1.16 SMBus

Table 4.16. SMBus Peripheral Timing Performance (Master Mode)

Parameter	Symbol	Test Condition	Min	Typ	Max	Unit
Standard Mode (100 kHz Class)						
I2C Operating Frequency	f_{I2C}		0	—	70[2]	kHz
SMBus Operating Frequency	f_{SMB}		40[1]	—	70[2]	kHz
Bus Free Time Between STOP and START Conditions	t_{BUF}		9.4	—	—	µs
Hold Time After (Repeated) START Condition	$t_{HD:STA}$		4.7	—	—	µs
Repeated START Condition Setup Time	$t_{SU:STA}$		9.4	—	—	µs
STOP Condition Setup Time	$t_{SU:STO}$		9.4	—	—	µs
Data Hold Time	$t_{HD:DAT}$		0	—	—	µs
Data Setup Time	$t_{SU:DAT}$		4.7	—	—	µs
Detect Clock Low Timeout	$t_{TIMEOUT}$		25	—	—	ms
Clock Low Period	t_{LOW}		4.7	—	—	µs
Clock High Period	t_{HIGH}		9.4	—	50[3]	µs
Fast Mode (400 kHz Class)						
I2C Operating Frequency	f_{I2C}		0	—	256[2]	kHz
SMBus Operating Frequency	f_{SMB}		40[1]	—	256[2]	kHz
Bus Free Time Between STOP and START Conditions	t_{BUF}		2.6	—	—	µs
Hold Time After (Repeated) START Condition	$t_{HD:STA}$		1.3	—	—	µs
Repeated START Condition Setup Time	$t_{SU:STA}$		2.6	—	—	µs
STOP Condition Setup Time	$t_{SU:STO}$		2.6	—	—	µs
Data Hold Time	$t_{HD:DAT}$		0	—	—	µs
Data Setup Time	$t_{SU:DAT}$		1.3	—	—	µs
Detect Clock Low Timeout	$t_{TIMEOUT}$		25	—	—	ms
Clock Low Period	t_{LOW}		1.3	—	—	µs
Clock High Period	t_{HIGH}		2.6	—	50[3]	µs

Note:

1. The minimum SMBus frequency is limited by the maximum Clock High Period requirement of the SMBus specification.
2. The maximum I2C and SMBus frequencies are limited by the minimum Clock Low Period requirements of their respective specifications.
3. SMBus has a maximum requirement of 50 µs for Clock High Period. Operating frequencies lower than 40 kHz will be longer than 50 µs. I2C can support periods longer than 50 µs.

4.3 Absolute Maximum Ratings

Stresses above those listed in Table 4.19 Absolute Maximum Ratings on page 32 may cause permanent damage to the device. This is a stress rating only and functional operation of the devices at those or any other conditions above those indicated in the operation listings of this specification is not implied. Exposure to maximum rating conditions for extended periods may affect device reliability. For more information on the available quality and reliability data, see the Quality and Reliability Monitor Report at http://www.silabs.com/support/quality/pages/default.aspx.

Table 4.19. Absolute Maximum Ratings

Parameter	Symbol	Test Condition	Min	Max	Unit
Ambient Temperature Under Bias	T_{BIAS}		-55	125	°C
Storage Temperature	T_{STG}		-65	150	°C
Voltage on VDD	V_{DD}		GND-0.3	4.2	V
Voltage on VIO[2]	V_{IO}		GND-0.3	V_{DD}+0.3	V
Voltage on I/O pins or RSTb, excluding P2.0-P2.3 (QFN24 and QSOP24) or P3.0-P3.3 (QFN32 and QFP32)	V_{IN}	V_{IO} > 3.3 V	GND-0.3	5.8	V
		V_{IO} < 3.3 V	GND-0.3	V_{IO}+2.5	V
Voltage on P2.0-P2.3 (QFN24 and QSOP24) or P3.0-P3.3 (QFN32 and QFP32)	V_{IN}		GND-0.3	V_{DD}+0.3	V
Total Current Sunk into Supply Pin	I_{VDD}		—	200	mA
Total Current Sourced out of Ground Pin	I_{GND}		200	—	mA
Current Sourced or Sunk by any I/O Pin or RSTb	I_{IO}		-100	100	mA
Operating Junction Temperature	T_J	T_A = -40 °C to 85 °C	–40	105	°C
		T_A = -40 °C to 125 °C (I-grade parts only)	-40	130	°C

Note:

1. Exposure to maximum rating conditions for extended periods may affect device reliability.
2. In certain package configurations, the VIO and VDD supplies are bonded to the same pin.

5. Typical Connection Diagrams

5.1 Power

Figure 5.1 Power Connection Diagram on page 33 shows a typical connection diagram for the power pins of the device.

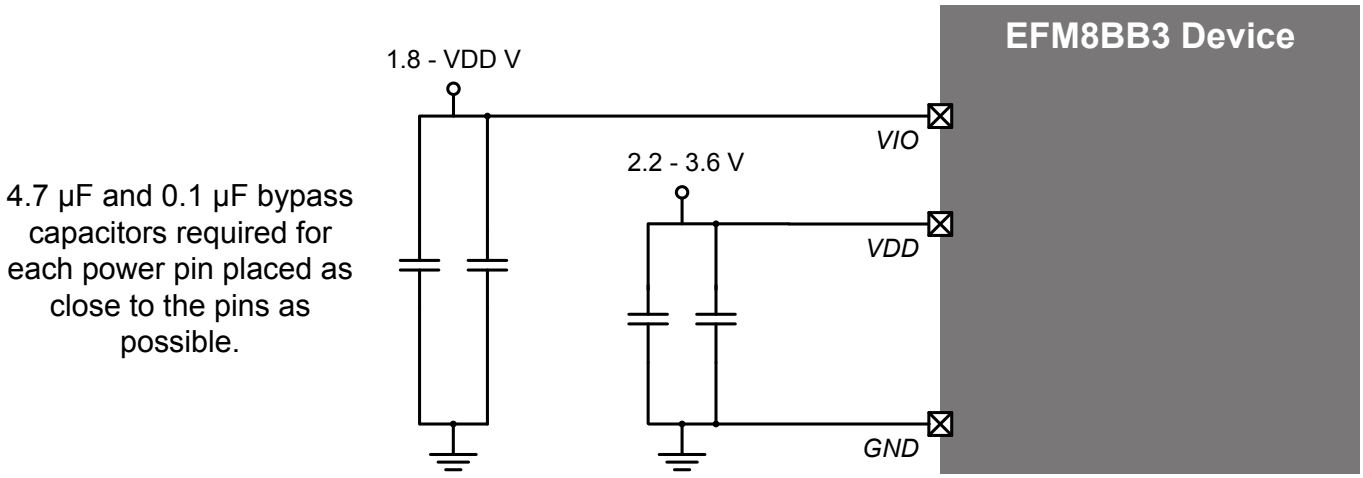


Figure 5.1. Power Connection Diagram

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
6	P3.7 / C2D	Multifunction I/O / C2 Debug Data			
7	P3.3	Multifunction I/O			DAC3
8	P3.2	Multifunction I/O			DAC2
9	P3.1	Multifunction I/O			DAC1
10	P3.0	Multifunction I/O			DAC0
11	P2.6	Multifunction I/O			ADC0.19 CMP1P.8 CMP1N.8
12	P2.5	Multifunction I/O		CLU3OUT	ADC0.18 CMP1P.7 CMP1N.7
13	P2.4	Multifunction I/O			ADC0.17 CMP1P.6 CMP1N.6
14	P2.3	Multifunction I/O	Yes	P2MAT.3 CLU1B.15 CLU2B.15 CLU3A.15	ADC0.16 CMP1P.5 CMP1N.5
15	P2.2	Multifunction I/O	Yes	P2MAT.2 CLU2OUT CLU1A.15 CLU2B.14 CLU3A.14	ADC0.15 CMP1P.4 CMP1N.4
16	P2.1	Multifunction I/O	Yes	P2MAT.1 I2C0_SCL CLU1B.14 CLU2A.15 CLU3B.15	ADC0.14 CMP1P.3 CMP1N.3
17	P2.0	Multifunction I/O	Yes	P2MAT.0 I2C0_SDA CLU1A.14 CLU2A.14 CLU3B.14	CMP1P.2 CMP1N.2

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
18	P1.7	Multifunction I/O	Yes	P1MAT.7 CLU0B.15 CLU1B.13 CLU2A.13	ADC0.13 CMP0P.9 CMP0N.9
19	P1.6	Multifunction I/O	Yes	P1MAT.6 CLU0A.15 CLU1B.12 CLU2A.12	ADC0.12
20	P1.5	Multifunction I/O	Yes	P1MAT.5 CLU0B.14 CLU1A.13 CLU2B.13	ADC0.11
21	P1.4	Multifunction I/O	Yes	P1MAT.4 CLU0A.14 CLU1A.12 CLU2B.12	ADC0.10
22	P1.3	Multifunction I/O	Yes	P1MAT.3 CLU0B.13 CLU1B.11 CLU2B.11 CLU3A.13	ADC0.9
23	P1.2	Multifunction I/O	Yes	P1MAT.2 CLU0A.13 CLU1A.11 CLU2B.10 CLU3A.12	ADC0.8 CMP0P.8 CMP0N.8
24	P1.1	Multifunction I/O	Yes	P1MAT.1 CLU0B.12 CLU1B.10 CLU2A.11 CLU3B.13	ADC0.7 CMP0P.7 CMP0N.7

Pin Number	Pin Name	Description	Crossbar Capability	Additional Digital Functions	Analog Functions
11	P2.1	Multifunction I/O	Yes	P2MAT.1 CLU1B.14 CLU2A.15 CLU3B.15	DAC1
12	P2.0	Multifunction I/O	Yes	P2MAT.0 CLU1A.14 CLU2A.14 CLU3B.14	DAC0
13	P1.7	Multifunction I/O	Yes	P1MAT.7 CLU0B.15 CLU1B.13 CLU2A.13	ADC0.12 CMP1P.6 CMP1N.6
14	P1.6	Multifunction I/O	Yes	P1MAT.6 CLU3OUT CLU0A.15 CLU1B.12 CLU2A.12	ADC0.11 CMP1P.5 CMP1N.5
15	P1.5	Multifunction I/O	Yes	P1MAT.5 CLU2OUT CLU0B.14 CLU1A.13 CLU2B.13	ADC0.10 CMP1P.4 CMP1N.4
16	P1.4	Multifunction I/O	Yes	P1MAT.4 I2C0_SCL CLU0A.14 CLU1A.12 CLU2B.12	ADC0.9 CMP1P.3 CMP1N.3
17	P1.3	Multifunction I/O	Yes	P1MAT.3 I2C0_SDA CLU0B.13 CLU1B.11 CLU2B.11 CLU3A.13	CMP1P.2 CMP1N.2

Dimension	Min	Typ	Max

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC Solid State Outline MO-220.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020C specification for Small Body Components.

8. QFP32 Package Specifications

8.1 QFP32 Package Dimensions

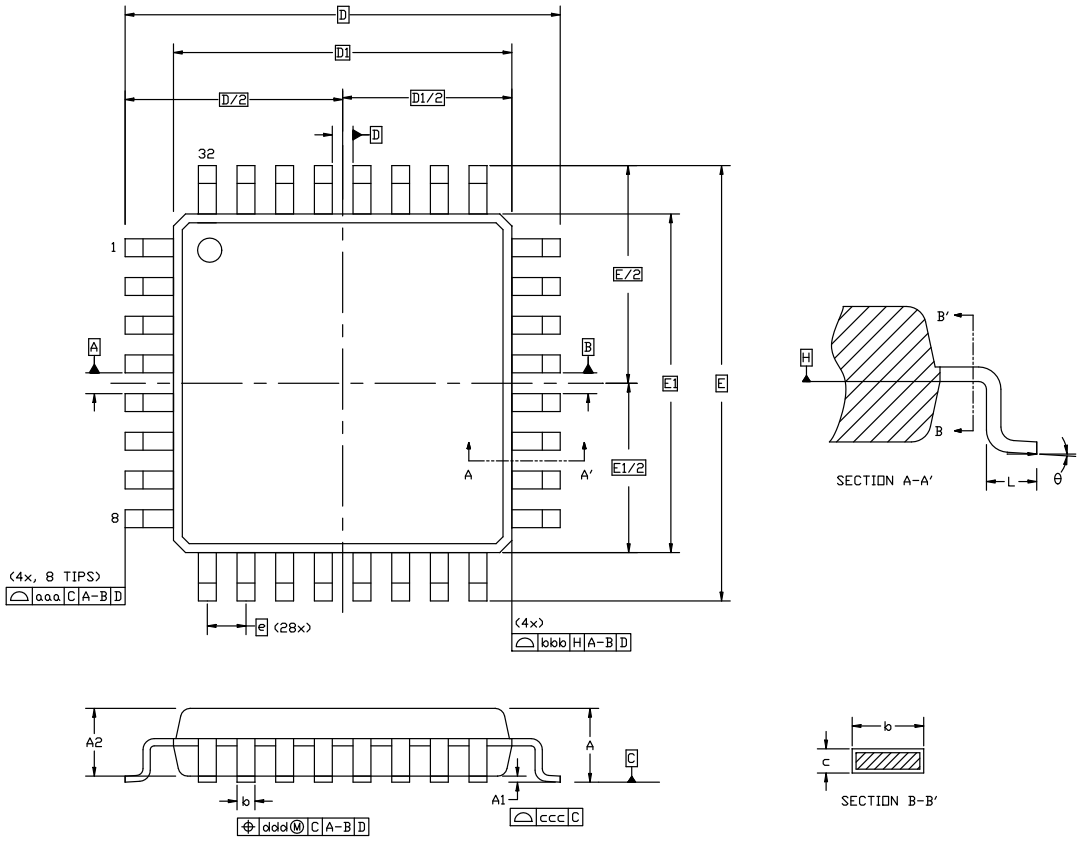


Figure 8.1. QFP32 Package Drawing

Table 8.1. QFP32 Package Dimensions

Dimension	Min	Typ	Max
A	—	—	1.20
A1	0.05	—	0.15
A2	0.95	1.00	1.05
b	0.30	0.37	0.45
c	0.09	—	0.20
D	9.00 BSC		
D1	7.00 BSC		
e	0.80 BSC		
E	9.00 BSC		
E1	7.00 BSC		
L	0.50	0.60	0.70

Dimension	Min	Typ	Max
aaa		0.20	
bbb		0.20	
ccc		0.10	
ddd		0.20	
theta	0°	3.5°	7°

Note:

1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC outline MS-026.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

9. QFN24 Package Specifications

9.1 QFN24 Package Dimensions

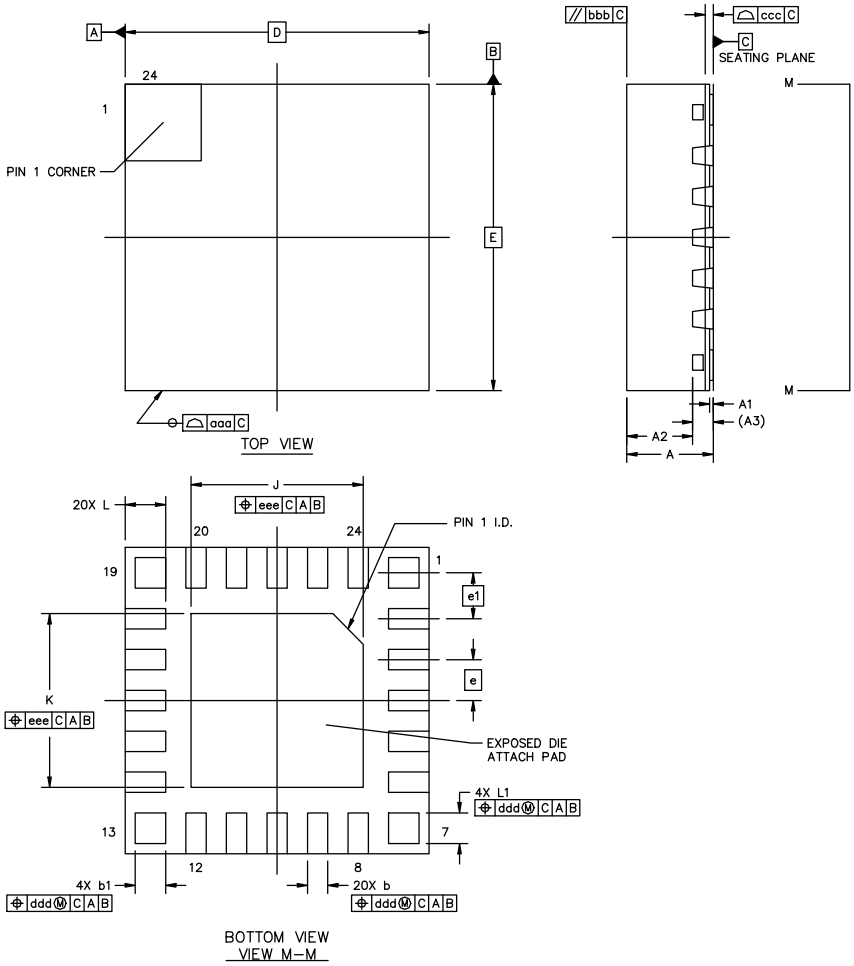


Figure 9.1. QFN24 Package Drawing

Table 9.1. QFN24 Package Dimensions

Dimension	Min	Typ	Max
A	0.8	0.85	0.9
A1	0.00	—	0.05
A2	—	0.65	—
A3		0.203 REF	
b	0.15	0.2	0.25
b1	0.25	0.3	0.35
D		3.00 BSC	
E		3.00 BSC	

Dimension	Min	Typ	Max
aaa		0.20	
bbb		0.18	
ccc		0.10	
ddd		0.10	

Note:

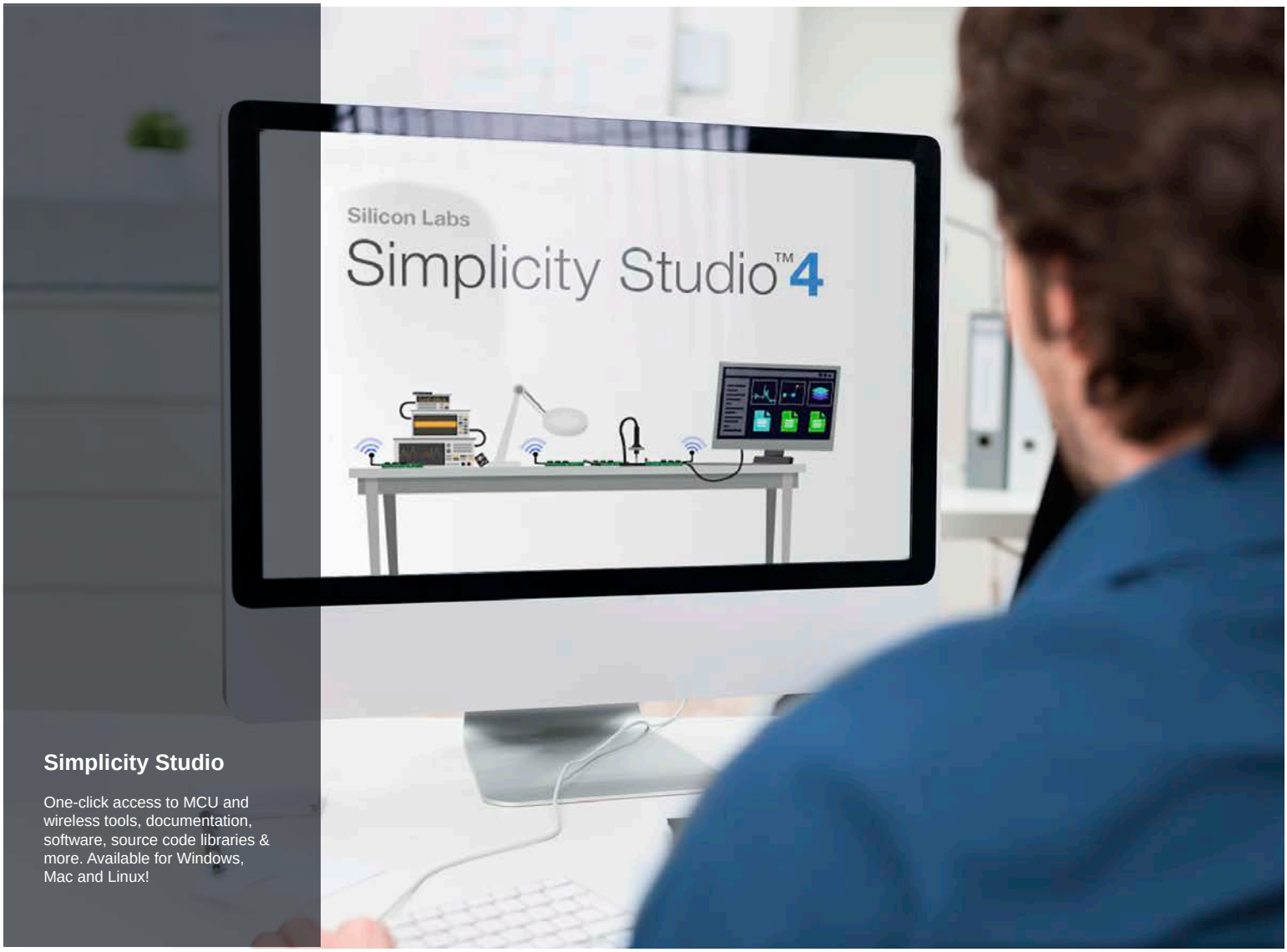
1. All dimensions shown are in millimeters (mm) unless otherwise noted.
2. Dimensioning and Tolerancing per ANSI Y14.5M-1994.
3. This drawing conforms to JEDEC outline MO-137, variation AE.
4. Recommended card reflow profile is per the JEDEC/IPC J-STD-020 specification for Small Body Components.

10.3 QSOP24 Package Marking

Figure 10.3. QSOP24 Package Marking

The package marking consists of:

- PPPPPPPP – The part number designation.
- TTTTTT – A trace or manufacturing code.
- YY – The last 2 digits of the assembly year.
- WW – The 2-digit workweek when the device was assembled.
- # – The device revision (A, B, etc.).



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